VIRTUAL TRAINING COURSE, 27 October 2020

METROLOGY FOR MEASUREMENT OF NANOPARTICLE SIZE BY ELECTRON MICROSCOPY & ATOMIC FORCE MICROSCOPY

To join this free virtual training course please send the registration form before 23 October to:

Marion de Niet (mdniet@vsl.nl)

so we can invite you to participate.

Agenda

27 October 2020, afternoon

Time (CET)	Activity
13:00 - 13:05	Opening – R. Koops (VSL)
13:05 - 13:20	The EMPIR project nPSize – D. Hodoroaba (BAM)
13:20 - 13:45	Metrology of SEM measurements of nanoparticles – L. Crouzier (LNE)
13:45 - 14:10	Metrology of TSEM measurements of nanoparticles – T. Klein (PTB)
14:10 - 14:35	Metrology of AFM measurements of nanoparticles – R. Koops (VSL)
14:35 - 14:50	Sample preparation – C. Hörenz (BAM)
14:50 - 15:15	Break
15:15 - 15:35	Hybrid methods for microscopy of nanoparticles (SEM/TSEM/AFM) – N. Feltin, D. Hodoroaba et al. (LNE/BAM/SMD)
15:35 - 16:00	Machine learning in Nanoparticle Metrology – Julien Baderot (POLLEN)
16:00 - 16:20	VAMAS RRT for Shape and Size Analysis of Nano-particles by Atomic Force Microscopy – Dr. Daisuke Fujita (NIMS)
16:20 - 16:40	OECD projects on nanoparticle characterisation – A. Schmidt (BAM)
16:40 - 17:00	In-situ nano particle metrology using traceable flow cytometry – A. van de Nes (VSL)
17:00 - 17:05	Closing statements – R. Koops (VSL)